

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10786900	HUANG, WEI-FENG
	Examiner	Art Unit
	Yeh, Eueng-nan	2624

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
EAST text search - see search history outputs	2007/06/13	ey
PALM inventor search - see search history outputs	2007/06/13	ey
SPIE Digital Library search - see search history outputs	2007/06/19	ey
EAST text search - see search printouts	2007/10/10	ey
EAST text search - see search outputs	2008/03/27	ey
EAST text search - see search history printouts	2008.11.18	ey
Japan paten search - see search history printoutst	2008.11.19	ey

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

--	--